

10/807,692

Interference

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L10	2	((inspecting adj circuit) and (signal adj lines)).dm.	US-PGPUB	OR	ON	2006/07/17 16:00
L13	8	((signal adj lines) and (first adj NAND) and (second adj NAND) and (third adj NAND)).dm.	US-PGPUB	OR	ON	2006/07/17 16:03
L14	1	((source adj driver) and (clock adj signal) and (start adj pulse) and (video adj signal)).dm.	US-PGPUB	OR	ON	2006/07/17 16:04

update

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EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	19	(NAND near gate\$1) and (input near terminal\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/17 14:55
L2	14438	(NAND near gate\$1) and (input near terminal\$1) and (output near terminal\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/17 14:55
L3	204187	((("326") or ("327") or ("345")).CLAS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/07/17 14:55
L4	3793	L2 and L3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/17 14:55
L5	146	L4 and (NAND near logic near gate\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/17 14:56
L6	474	L4 and (NOR near gate\$1) and inverter and (comparing or comparison)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/17 14:58
L7	53934	(liquid near crystal near display) same (screen\$3 or inspect\$3 or detect\$3 or test\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/17 15:01
L8	1573	L7 same (defect\$2 or damage\$2 or scrap)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/17 15:01
L9	207	L8 same (compar\$5 or determin\$5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/17 15:01